

Special Session on Computer Vision Based Measurements October 4–6, 2016 2016 IEEE International Conference on Imaging Systems (IST 2016) Chania, Crete Island, Greece

1. Introduction

Bringing computer vision based measurements into our life has been challenging researchers in industry and in academia over the past few decades. Rapid developments in imaging devices and computing systems have turned computer vision based instruments into a viable option, providing new solutions to known problems. In this context, computer vision is a generic tool that can be used to measure and monitor phenomena in a wide range of domains.

The goal of this special session is to bring together researchers and practitioners working in the area of *Computer Vision Based Measurements*. We are soliciting original contributions, which address a wide range of theoretical and practical issues related to the application of computer vision to instrumentation and measurement including, but not limited to:

- ▷ Three-dimensional capture and processing (e.g. volume, distance, etc.)
- ▷ Computer vision based parameter estimation (e.g. pose, location, etc.)
- ▷ Computer vision based instruments in traffic monitoring
- ▶ Computer vision based instruments in safety

- ▷ Computer vision based instruments in assistive technologies
- > Applications and future trends

2. Paper Submission

Prospective authors are invited to submit papers of no more than 6 pages including results, figures and references. In submitting a manuscript to IST 2016 Special Session on Computer Vision Based Measurements, the authors acknowledge that no paper substantially similar in content has been or will be submitted to another conference during the IST 2016 review period. All papers, regardless to whether accepted as orals or posters, will appear in the symposium proceedings, and their extended versions may be selected to appear in Special Issues that will be published by "Biomedical Signal Processing and Control (BSPC)", Elsevier, and "Multimedia Tools and Applications (MTAP)", Springer. More paper submission information is available at:

http://ist2016.ieee-ims.org/special-session-computer-vision-based-measurements

3. Important Dates

Submission of full-length papers: June 6, 2016 Notification of acceptance: June 20, 2016

Submission of camera-ready papers: July 20, 2016

4. Special Session Organizers

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